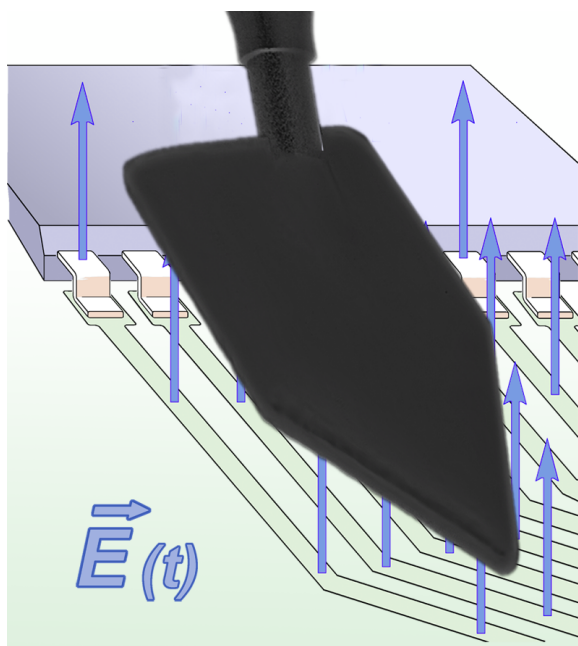


RF-E 02

E-Field Probe 30 MHz up to 1.5 GHz

LANGER
EMV-Technik



Short description

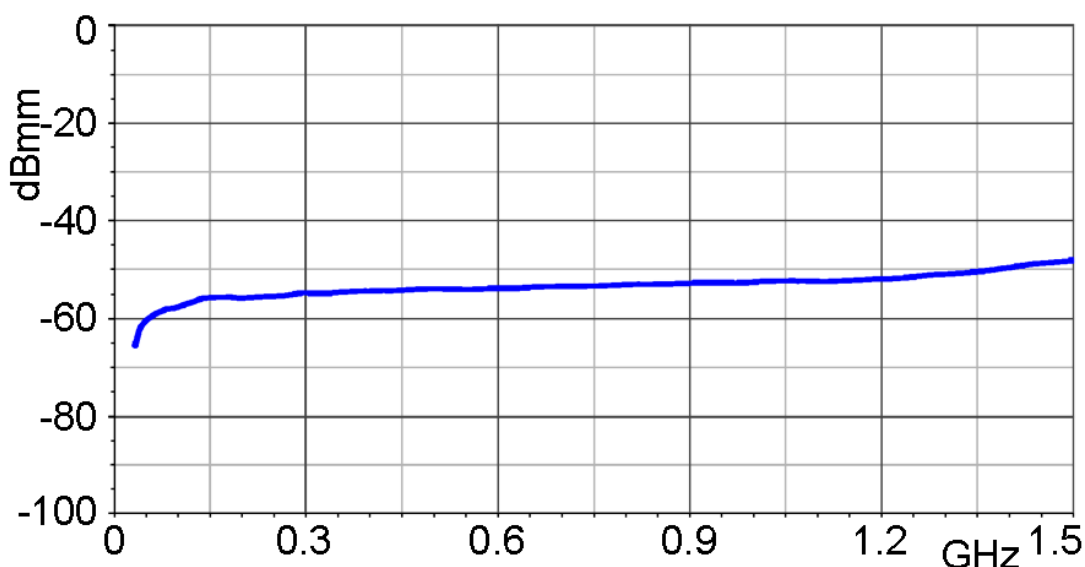
The RF-E 02 near-field probe detects electrical fields that are decoupled from bus structures, larger components or supply surfaces. The electrode surface on the underside of the probe tip is approx. 2 cm x 5 cm. The probe functions best within distances of 1 cm - 2 cm from the component.

The RF-E 02 is a passive near-field probe. In principle it has the same structure as the RF-E 05 and RF-E 10 probes. When measuring, the bottom surface of the probe head is positioned close to the measured object. This allows the E-field emitted by an assembly to be detected. To achieve a higher resolution, only the tip of the probe head should be held toward the measured object. The near-field probe is small and handy. It has a current attenuating sheath and, therefore, is electrically shielded. It can be connected to a spectrum analyzer or an oscilloscope with a 50 Ω input. The H-field probe does not have an internal terminating resistance of 50 Ω .

Technical parameters

Frequency range	30 MHz - 1.5 GHz
Probe head dimensions	$\approx (23 \times 53)$ mm
Connector - output	SMB, male, jack

Frequency response [dB μ V] / [dB μ V/mm]

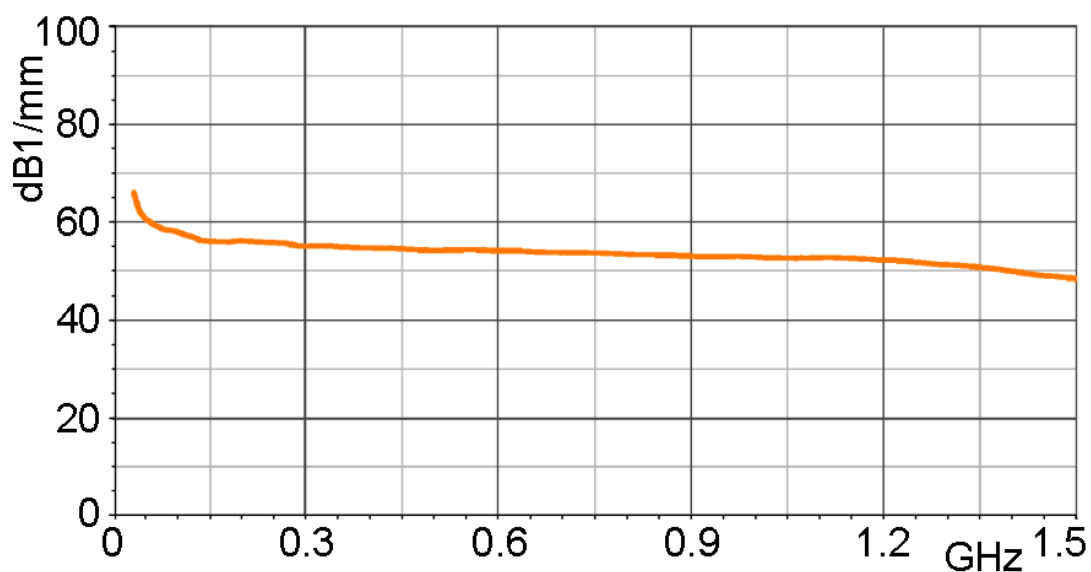


RF-E 02

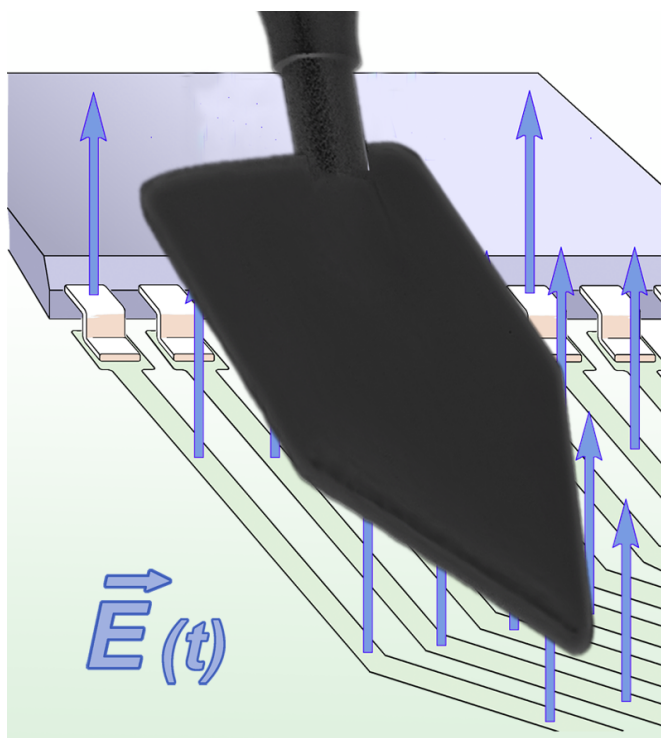
E-Field Probe 30 MHz up to 1.5 GHz

LANGER
EMV-Technik

E- field correction curve [dB μ V/mm] / [dB μ V]



Measuring principles



RF-E 02

E-Field Probe 30 MHz up to 1.5 GHz

LANGER
EMV-Technik

Probe head

